

ADVANCED CHARACTERIZATION PLATFORM

The **Advanced Characterization Platform** is equipped with a wide range of cutting-edge instruments. Standard and tailored methodologies are used to investigate elemental or molecular composition and quantification, structure identification, topography, morphological characterization and to perform 2D/3D Imaging.

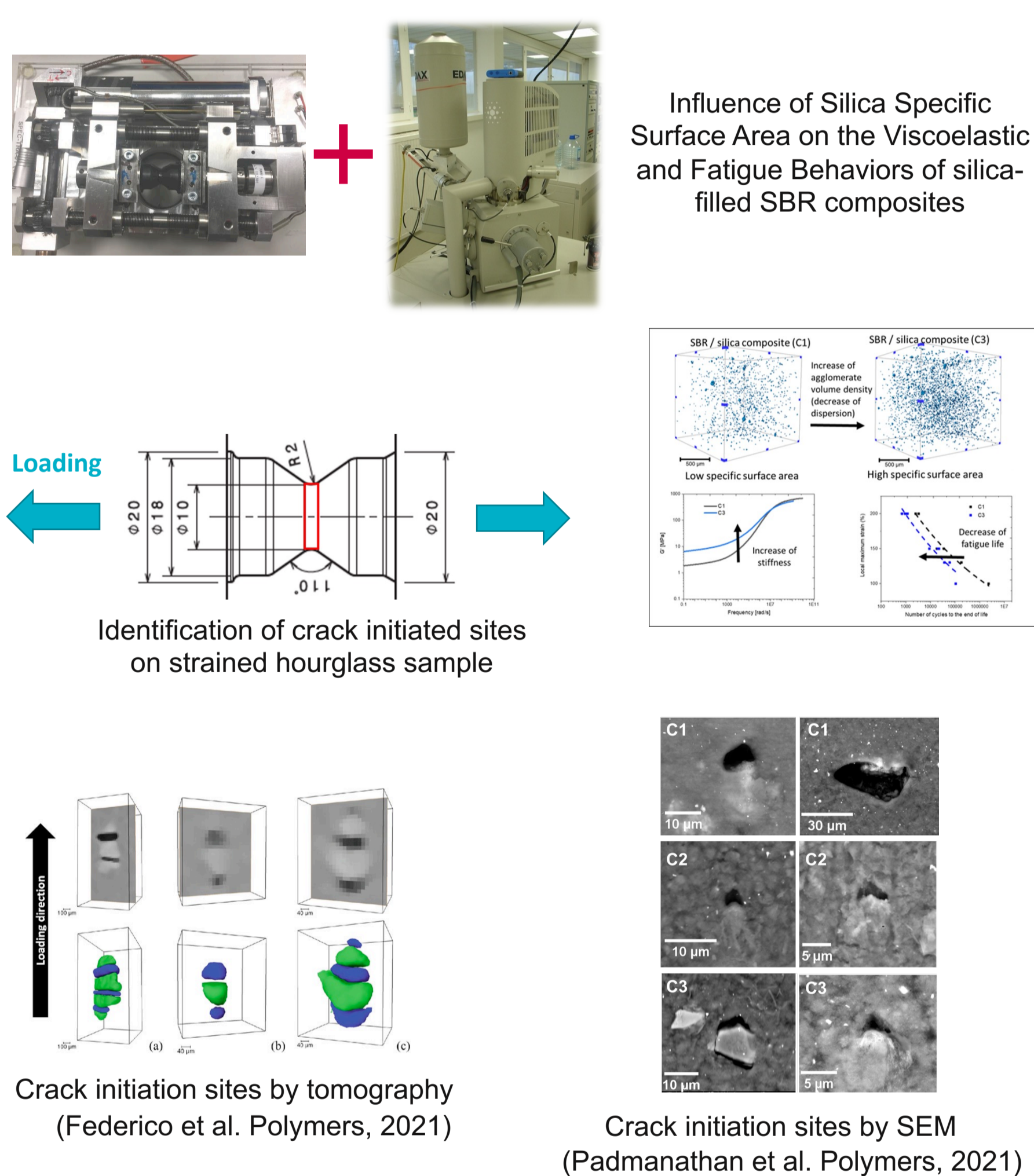
Structure and Morphology
{TEM, SEM, Tomo, XRD}

Reverse Engineering
{HRMS, NMR, LC/SEC}

**Research
&
Activity
Fields**

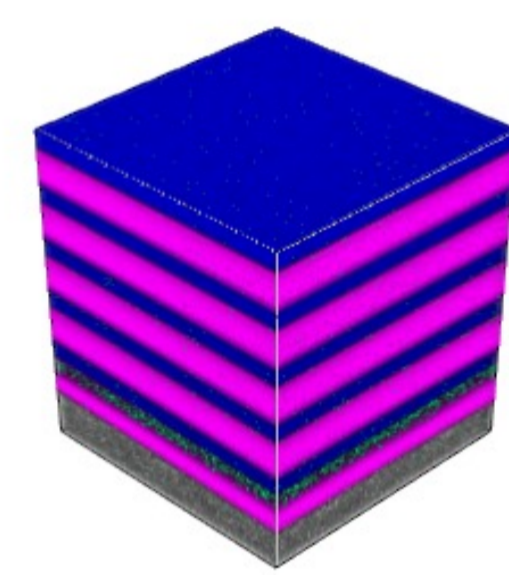
Imaging
From μm to nm
2D/3D

Structure & Morphology



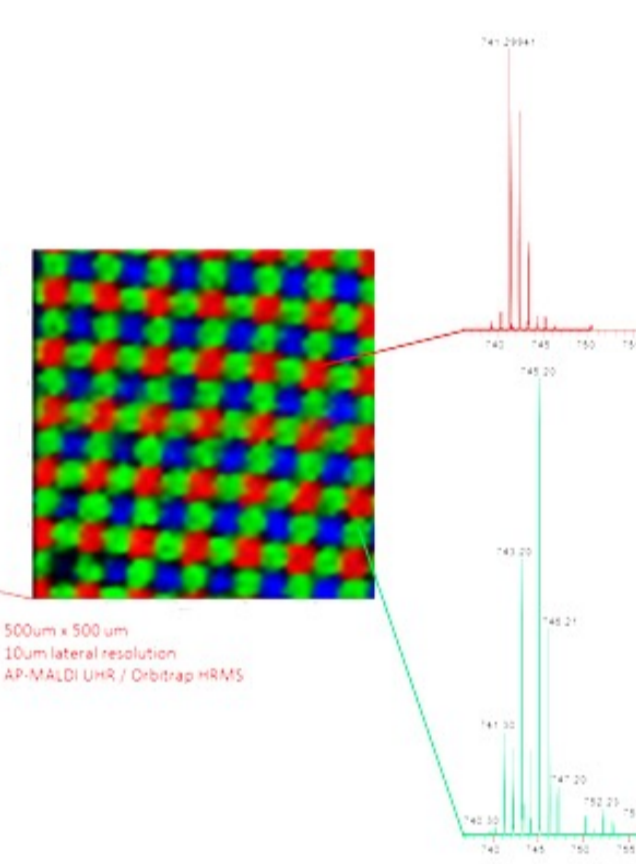
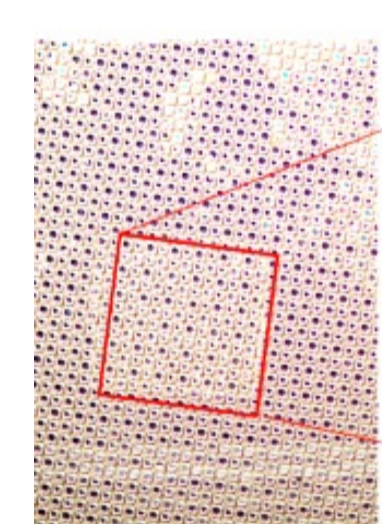
2D/3D imaging

TOFSIMS multilayer 3D imaging



TOFSIMS 3D reconstructed data cube. Alternating $\text{ZnO}/\text{Al}_2\text{O}_3$ ALD layers (5x50nm each). Hydrocarbon contamination is detected in a specific interlayer.

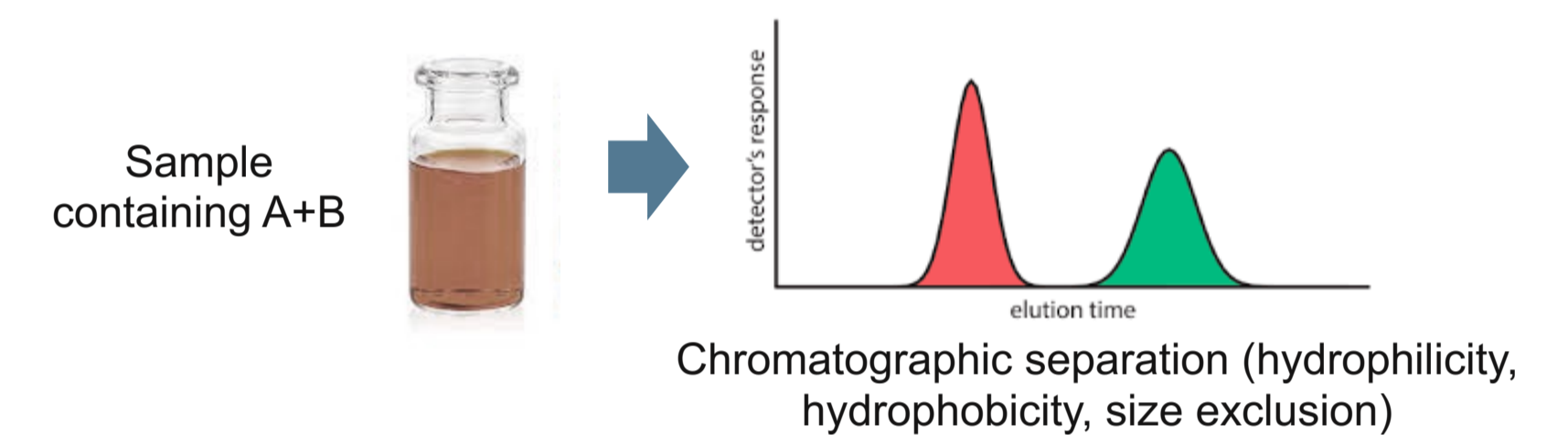
AP-MALDI Orbitrap imaging



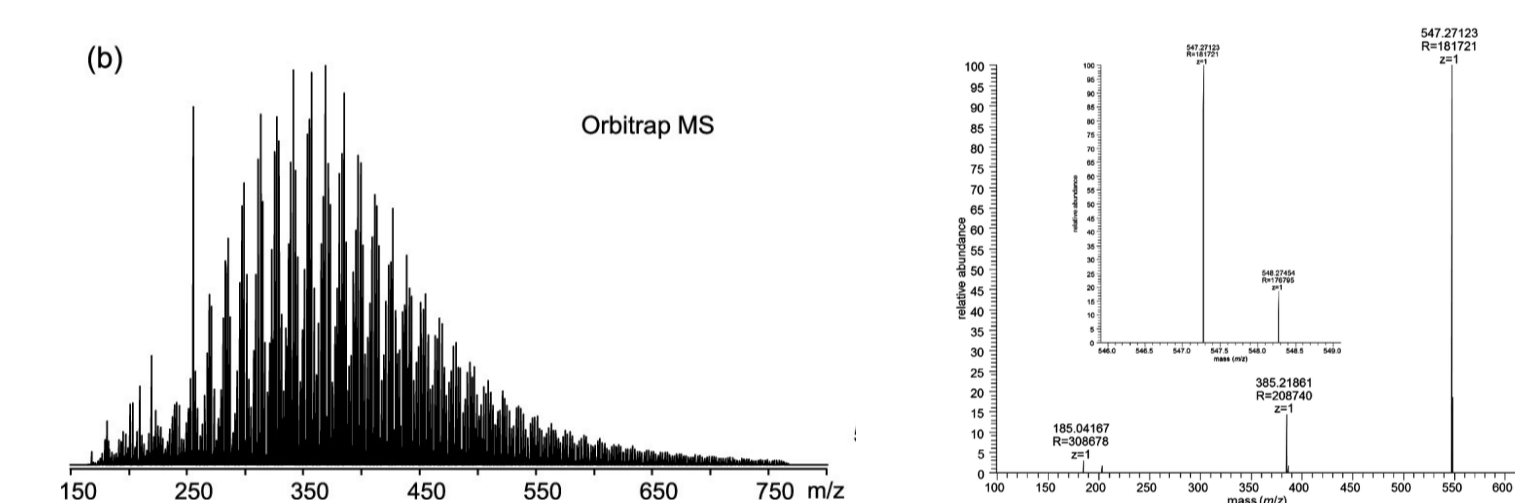
- Part of a broken smartphone display
- 10-micron lateral resolution APMALDI UHR imaging with Orbitrap detection
- AP-LDI / Orbitrap:
 - Exact m/z measurement (<1ppm)
 - MS/MS confirmation
 - Identification of degradation products

Reverse Engineering

Multi-mode Chromatography



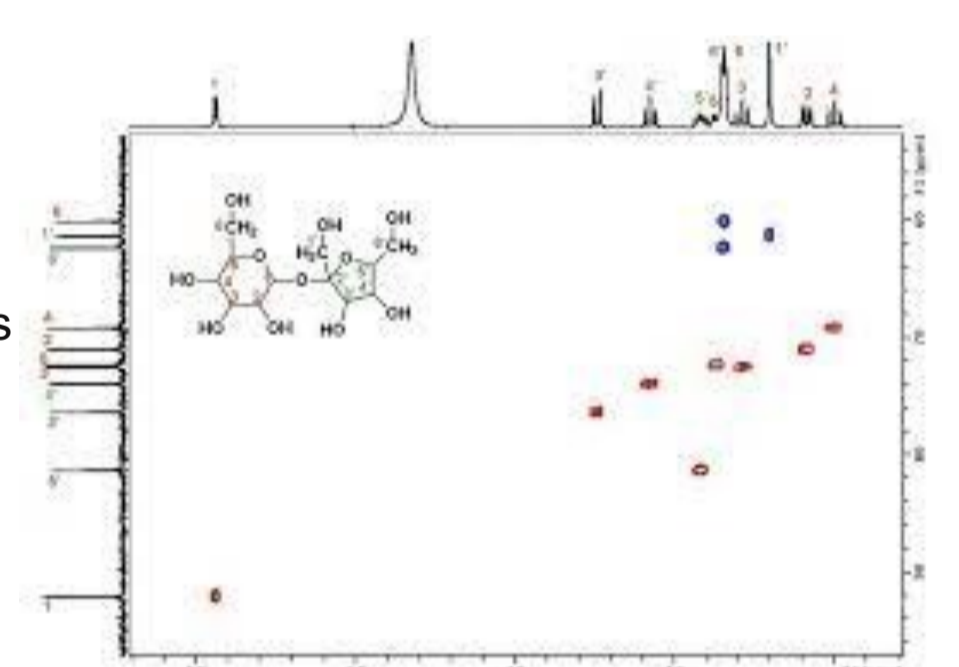
High resolution Mass spectrometry



High resolution mass spectrometry (Orbitrap) identification of individual ingredients (exact m/z + structural analysis by MSMS) for oligomers and small molecules

Nuclear Magnetic resonance

Comprehensive structural analysis of molecular structures. Example of two-dimensional (2D) HSQC with proton (^1H) and ^{13}C



From micro to nano- imaging

